Scanning Probe Microscopy System (SPM): Agilent 5500 AFM

Department of Magnetism, IEP SAS, Watsonova 47

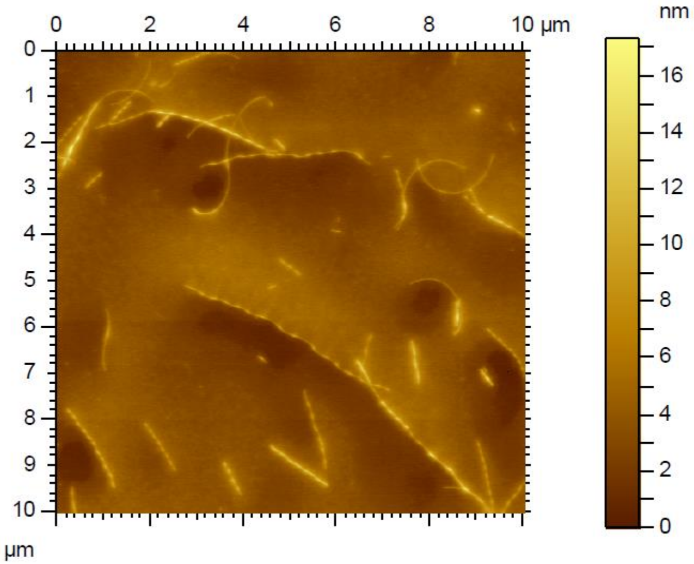
Responsible : I. Baťko, batko@saske.sk

SPM system comprising STM and AFM supports following **basic measurement modes**:

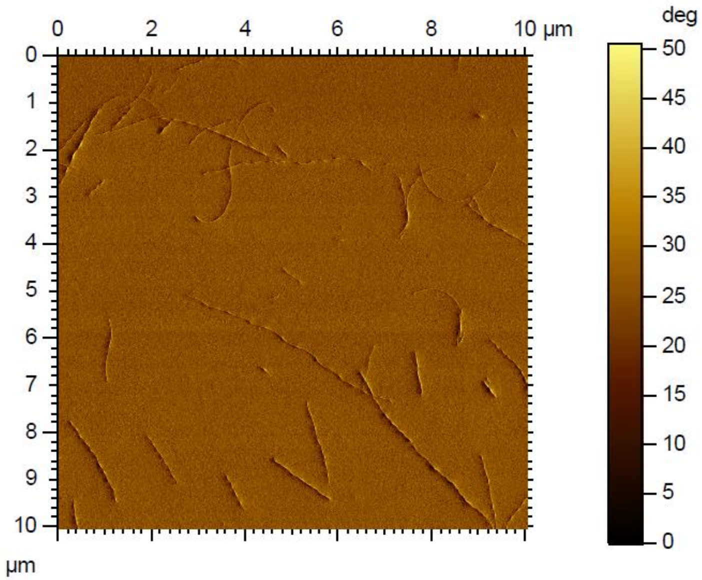
- contact
- lateral force
- tapping
- non-contact
- phase imaging

and advanced modes:

- MFM (Magnetic)
- EFM (Electric)
- KFM (Kelvin)
- PFM (Piezo)



Obr. 1a)   Fibriles on mica, topography (tapping mode).



Obr.1b)   Fibriles on mica, phase image (tapping mode).

Besides measurements at ambient temperature in air the system also enables :

- AFM measurements in controlled environment (using environmental isolation chamber and glove box)
- AFM measurements in liquids (using static as well continuous liquid cell)
- Realization of measurements in temperature range between -30°C and 250°C